

Referenčna oznaka	Naslov
47/2476/NP	PNW 47-2476: Semiconductor devices – The classification of defects in gallium nitride epitaxial wafers on silicon carbide substrate
47/2478/NP	PNW 47-2478: SEMICONDUCTOR DEVICES – Non-destructive recognition criteria of defects in silicon carbide homoepitaxial wafer for power devices - Part 3: Test method for defects using photoluminescence
48B/2649/NP	Replaced by 48B/2649A/NP
48B/2649A/NP	PNW 48B-2649: IEC 63171-4/ED.1 Connector for electrical and electronic equipment - Detail specification for 2-way, shielded and unshielded, free and fixed connectors for data transmission up to 2000MHz with current carrying capability
48B/2650/NP	PNW 48B-2650: Connectors for electrical and electronic equipment - Tests and measurements – Part 27-200: Additional specifications for signal integrity tests up to 2 000 MHz on IEC 60603-7 series connectors – Tests 27a to 27g
48B/2651/NP	PNW 48B-2651: IEC 63171-3/ED.1: Connectors for electronic equipment – Product requirements - Part 1: Detail specification for 2-way, shielded free and fixed connectors for data transmissions with frequencies up to 600 MHz and current carrying capacity.
48B/2653/NP	PNW 48B-2653: IEC 63171-5/ED.1: CONNECTORS FOR ELECTRICAL AND ELECTRONIC EQUIPMENT – PRODUCT REQUIREMENTS –Part x-y: Detail specification for circular connectors with up to 8 ways, screw-locking, free and fixed connectors for data transmission up to 2000MHz with current carrying capacity
49/1284/NP	PNW TS 49-1284: Piezoelectric, dielectric and electrostatic devices and associated materials for frequency control, selection and detection - Glossary - Part 4-5: Piezoelectric sensors
62B/1091/NP	PNW 62B-1091: EVALUATION AND ROUTINE TESTING IN MEDICAL IMAGING DEPARTMENTS – Acceptance testing and quality control of DENTAL EXTRA-ORAL X-RAY EQUIPMENT used with DENTAL CONE BEAM COMPUTED TOMOGRAPHY
62B/1093/NP	PNW 62B-1093: Medical electrical equipment - Medical image display systems - Acceptance and constancy tests
65A/867/NP	PNW TS 65A-867: Requirements and Guidance in the use of mathematical and logical techniques for establishing exact properties of software and its documentation
69/593/NP	PNW 69-593: Electrical characteristics test methods of EDLC Module for Electric road vehicles
113/422/NP	PNW 113-422: IEC TS 62607-4-8: Nanomanufacturing - Key control characteristics – Part 4-8: Nano-enabled electrical energy storage devices - Determination of water content for electrode nanomaterials by the Karl Fischer Method
121A/219/NP	PNW TS 121A-219: Security aspects of switchgear and controlgear